

Measurement of sub-foveal choroidal thickness from optical low coherence reflectometry biometry: a new method (Erratum)

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[Proceedings Volume 12360, Ophthalmic Technologies XXXIII](#); 123600P (2023)

<https://doi.org/10.1117/12.2651145>

Event: SPIE BIOS, 2023, San Francisco, California, United States

Online Publication Date: 14 March 2023

Erratum Published: 5 May 2023

A revised version of this manuscript was published on 5 May 2023. Details of the revision are provided in the text that accompanies this Erratum. The original paper has been updated.